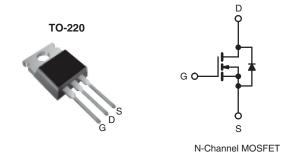




Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	100			
$R_{DS(on)}\left(\Omega\right)$	$V_{GS} = 5.0 \text{ V}$	0.077		
Q _g (Max.) (nC)	64			
Q _{gs} (nC)	9.4			
Q _{gd} (nC)	27			
Configuration	Single			



FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Logic-Level Gate Drive
- R_{DS(on)} Specified at V_{GS} = 4 V and 5 V
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRL540PbF
Lead (Fb)-liee	SiHL540-E3
SnPb	IRL540
SILL	SiHL540

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	100	V	
Gate-Source Voltage			V _{GS}	± 10	V	
Continuous Drain Current	V _{GS} at 5.0 V	T _C = 25 °C	1-	28		
	VGS at 3.0 V	T _C = 100 °C	ΙD	20	Α	
Pulsed Drain Current ^a			I _{DM}	110		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	440	mJ	
Avalanche Current ^a			I _{AR}	28	А	
Repetitive Avalanche Energy ^a			E _{AR}	15	mJ	
Maximum Power Dissipation	T _C = 25 °C		P _D	150	W	
Peak Diode Recovery dV/dt ^c			dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C		
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d]	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Woulding Torque				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 25 V, starting T_J = 25 °C, L = 841 μ H, R_G = 25 Ω , I_{AS} = 28 A (see fig. 12c).
- c. $I_{SD} \le 28$ A, $dI/dt \le 170$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 175$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

Vishay Siliconix



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greasd Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0		

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT		
Static								
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	100	-	-	V		
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	-	0.12	-	V/°C		
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	2.0	V	
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 10 V		-	± 100	nA	
Zana Oata Wallana Busin Oamani		V _{DS} =	V _{DS} = 100 V, V _{GS} = 0 V		-	25		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V	V _{GS} = 0 V, T _J = 150 °C	-	-	250	μΑ	
Drain Course On State Registeres	Р	V _{GS} = 5.0 V	I _D = 17 A ^b	-	-	0.077		
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 4.0 V	I _D = 14 A ^b	-	-	0.11	Ω	
Forward Transconductance	9 _{fs}	V _{DS}	V _{DS} = 50 V, I _D = 17 A		-	-	S	
Dynamic								
Input Capacitance	C _{iss}	$V_{GS} = 0 V$,		-	2200	-	pF	
Output Capacitance	C _{oss}		$V_{DS} = 25 V$		560	-		
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	140	-		
Total Gate Charge	Qg			-	-	64		
Gate-Source Charge	Q _{gs}	V _{GS} = 5.0 V	$V_{GS} = 5.0 \text{ V}$ $I_D = 28 \text{ A}, V_{DS} = 80 \text{ V},$ see fig. 6 and 13 ^b		-	9.4	nC	
Gate-Drain Charge	Q_{gd}		gramma ra	-	-	27	1	
Turn-On Delay Time	t _{d(on)}		1		8.5	-	ns	
Rise Time	t _r	V_{DD} = 50 V, I_{D} = 28 A, R_{G} = 9.0 Ω , R_{D} = 1.7 Ω , see fig. 10 ^b		-	170	-		
Turn-Off Delay Time	t _{d(off)}			-	35	-		
Fall Time	t _f			-	807	-		
Internal Drain Inductance	L_{D}	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L _S			-	7.5	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol showing the		-	28	Α	
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	110		
Body Diode Voltage	V _{SD}	T _J = 25 °C	T _J = 25 °C, I _S = 28 A, V _{GS} = 0 V ^b		-	2.5	V	
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 28 A, dl/dt = 100 A/μs ^b		-	200	260	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.7	2.90	μC	
Forward Turn-On Time	t _{on}	Intrinsic tu	n-on is dominated by L _S and L _D)			_D)		

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

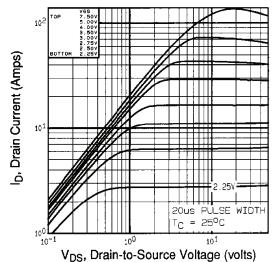


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

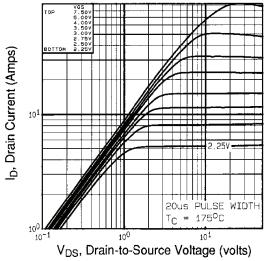


Fig. 2 - Typical Output Characteristics, $T_C = 175$ °C

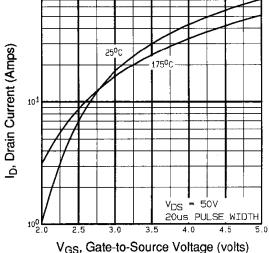


Fig. 3 - Typical Transfer Characteristics

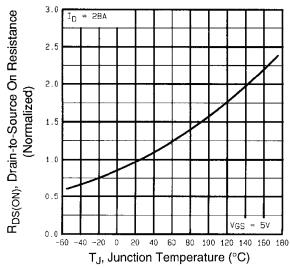


Fig. 4 - Normalized On-Resistance vs. Temperature

Vishay Siliconix



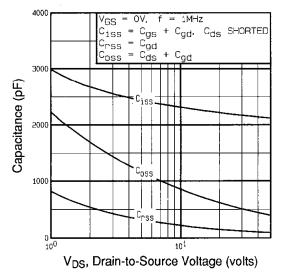


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

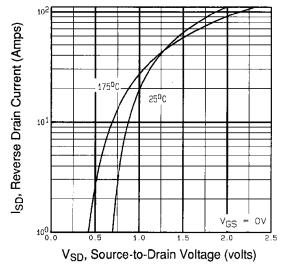


Fig. 7 - Typical Source-Drain Diode Forward Voltage

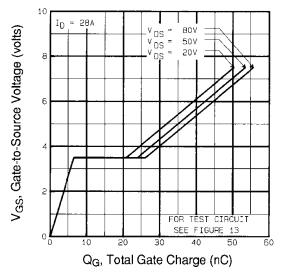


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

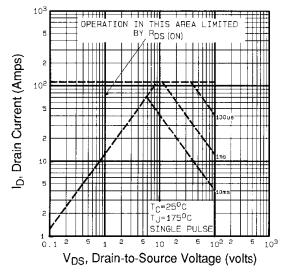
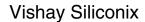


Fig. 8 - Maximum Safe Operating Area





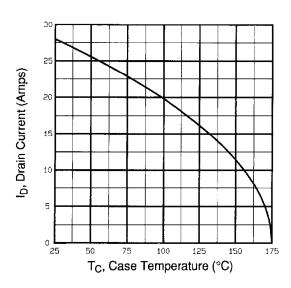


Fig. 9 - Maximum Safe Operating Area

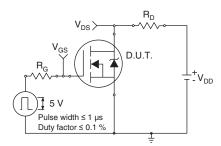


Fig. 10a - Switching Time Test Circuit

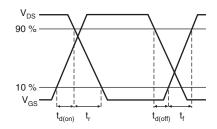


Fig. 10b - Switching Time Waveforms

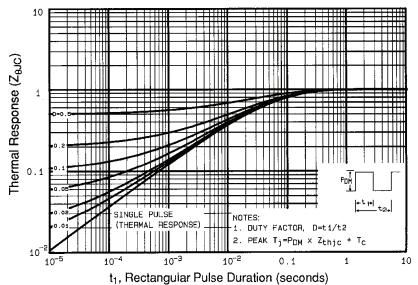


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

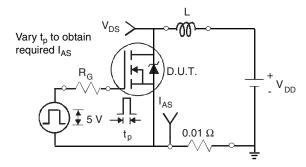


Fig. 12a - Unclamped Inductive Test Circuit

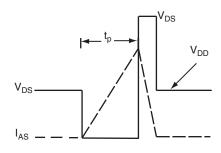


Fig. 12b - Unclamped Inductive Waveforms

Vishay Siliconix



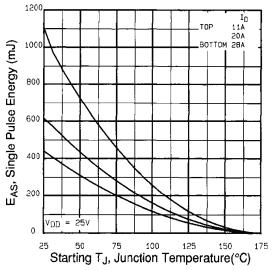


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

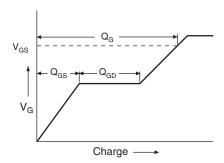


Fig. 13a - Basic Gate Charge Waveform

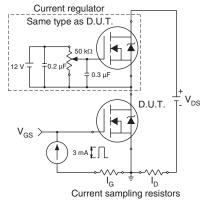
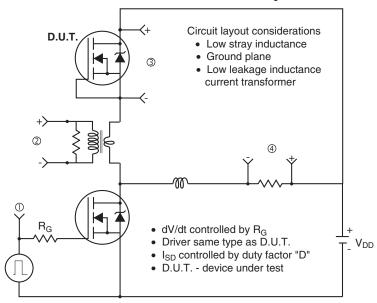
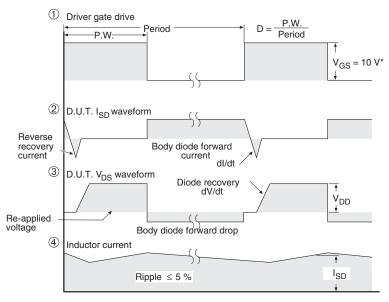


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?91300.



Vishav

Disclaimer

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.

Document Number: 91000 Revision: 18-Jul-08

www.DataSheet4U.com